









CD54AC74, CD74AC74

SCHS231E - NOVEMBER 1998 - REVISED AUGUST 2024

CDx4AC74 Dual Positive-Edge-Triggered D-Type Flip-Flops With Clear And Preset

1 Features

- AC types feature 1.5V to 5.5V operation and balanced noise immunity at 30% of the supply
- Speed of bipolar F, AS, and S, with significantly reduced power consumption
- Balanced propagation delays
- ±24mA output drive current fanout to 15 F
- SCR-latchup-resistant CMOS process and circuit design

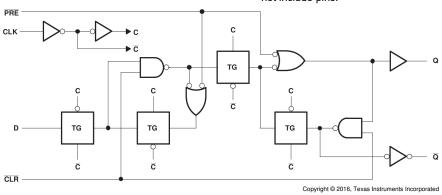
2 Description

The 'AC74 dual positive-edge-triggered devices are D-type flip-flops.

Device Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE(2)	BODY SIZE(3)
	J (CDIP, 14)	19.56mm × 7.9mm	19.56mm × 6.67mm
CDx4AC74	N (PDIP, 14)	19.3mm x 9.4mm	19.3mm x 6.35mm
	D (SOIC, 14)	8.65mm x 6mm	8.65mm x 3.9mm

- For more information, see Section 10. (1)
- (2) The package size (length × width) is a nominal value and includes pins, where applicable.
- (3) The body size (length × width) is a nominal value and does not include pins.



Logic Diagram, Each Flip-Flop (Positive Logic)



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3 Pin Configuration and Functions

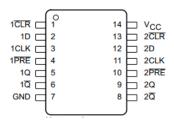


Figure 3-1. CD54AC74 F Package, 14-Pin CDIP; CD74AC74 E or M Package, 14-Pin PDIP or SOIC (Top View)

Pin Functions

	PIN	1/0	DESCRIPTION
NAME	NO.	 1/O	DESCRIPTION
1 CLR	1	Input	Channel 1, Clear Input, Active Low
1D	2	Input	Channel 1, Data Input
1CLK	3	Input	Channel 1, Positive edge triggered clock input
1 PRE	4	Input	Channel 1, Preset Input, Active Low
1Q	5	Output	Channel 1, Output
1 Q	6	Output	Channel 1, Inverted Output
GND	7	_	Ground
2 Q	8	Output	Channel 2, Inverted Output
2Q	9	Output	Channel 2, Output
2 PRE	10	Input	Channel 2, Preset Input, Active Low
2CLK	11	Input	Channel 2, Positive edge triggered clock input
2D	12	Input	Channel 2, Data Input
2 CLR	13	Input	Channel 2, Clear Input, Active Low
V _{CC}	14	_	Positive Supply



4 Specifications

4.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	6	V
I _{IK} 1	Input clamp current	$(V_1 < 0 \text{ or } V_1 > V_{CC})$		±20	mA
I _{OK} ¹	Output clamp current	$(V_O < 0 \text{ or } V_O > V_{CC})$		±50	mA
Io	Continuous output current	$(V_O = 0 \text{ to } V_{CC})$		±50	mA
	Continuous current through V	CC or GND		±100	mA
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

4.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

4.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1)

		,	T _A = 25°C		T _A = 25°C		−55°C 125°		-40°C to	85°C	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX			
V _{CC}	Supply voltage		1.5	5.5	1.5	5.5	1.5	5.5	V		
		V _{CC} = 1.5 V	1.2		1.2		1.2				
V _{IH}	High-level input voltage	V _{CC} = 3 V	2.1		2.1		2.1		V		
		V _{CC} = 5.5 V	3.85		3.85		3.85				
		V _{CC} = 1.5 V		0.3		0.3		0.3			
V _{IL}	Low-level input voltage	V _{CC} = 3 V		0.9		0.9		0.9	V		
		V _{CC} = 5.5 V		1.65		1.65		1.65			
VI	Input voltage		0	V _{CC}	0	V _{CC}	0	V _{CC}	V		
Vo	Output voltage		0	V _{CC}	0	V _{CC}	0	V _{CC}	V		
I _{OH}	High-level output current	V _{CC} = 4.5 V to 5.5 V		- 24		- 24		-24	mA		
I _{OL}	Low-level output current	V _{CC} = 4.5 V to 5.5 V		24		24		24	mA		
Λ+/Λ.,	Input transition rise or fall rate	V _{CC} = 1.5 V to 3 V		50		50		50	na/\/		
Δt/Δv	Input transition rise or fall rate	V _{CC} = 3.6 V to 5.5 V		20		20		20	ns/V		

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

4.4 Thermal Information

		CDx	4AC74		
THERMAL METRIC(1)		N (PDIP)	N (PDIP) D (SOIC)		
		14 PINS	14 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	80	119.9	°C/W	

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

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²⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

4.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{cc}	T _A = 25°C	−55°C to 125°C	-40°C to 85°C	UNIT	
				MIN MAX	MIN MAX	MIN MAX	
			1.5 V	1.4	1.4	1.4	
	l _c	I _{OH} = -50 μA	3 V	2.9	2.9	2.9	
			4.5 V	4.4	4.4	4.4	
V _{OH}	$V_I = V_{IH}$ or V_{IL}	I _{OH} = -4 mA	3 V	2.58	2.4	2.48	V
	I _{OH} = - 24 mA	4.5 V	3.94	3.7	3.8		
	$I_{OH} = -50 \text{ mA}^{(1)}$	5.5 V		3.85			
		$I_{OH} = -75 \text{ mA}^{(1)}$	5.5 V			3.85	
			1.5 V	0.1	0.1	0.1	
		I _{OL} = 50 μA	3 V	0.1	0.1	0.1	
			4.5 V	0.1	0.1	0.1	
V _{OL}	$V_I = V_{IH}$ or V_{IL}	I _{OL} = 12 mA	3 V	0.36	0.5	0.44	V
		I _{OL} = 24 mA	4.5 V	0.36	0.5	0.44	
		$I_{OL} = 50 \text{ mA}^{(1)}$	5.5 V		1.65		
		$I_{OL} = 75 \text{ mA}^{(1)}$	5.5 V			1.65	
I _I	V _I = V _{CC} or GND		5.5 V	±0.1	±1	±1	μA
Icc	$V_I = V_{CC}$ or GND,	I _O = 0	5.5 V	4	80	40	μA
Ci				10	10	10	pF

⁽¹⁾ Test one output at a time, not exceeding 1-second duration. Measurement is made by forcing indicated current and measuring voltage to minimize power dissipation. Test verifies a minimum 50-Ω transmission-line drive capability at 85°C and 75-Ω transmission-line drive capability at 125°C.

4.6 Timing Requirements, V_{CC} = 1.5 V

over recommended operating free-air temperature range, V_{CC} = 1.5 V (unless otherwise noted)

	1 0 1 0 0		−55°C to 125°C		−40°C to	UNIT	
			MI N	MAX	MIN	MAX	_
f _{clock}	Clock frequency			9		10	MHz
	Pulse duration	PRE or CLR low	50		44		ns
T _w	ruise duration	CLK	56		49		115
	Setup time	Data	44		39		ns
t _{su}	Setup time	PRE or CLR inactive					ns
t _h	Hold time	Data after CLK↑	0		0		ns
t _{rec}	Recovery time, before CLK↑	CLR↑ or PRE↑	34		30		ns

4.7 Timing Requirements, $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$

over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

			-55°C to 125°C		−40°C to	85°C	UNIT
			MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			79		90	MHz
	Pulse duration	PRE or CLR low	5.6		4.9		no
t _w	ruise duration	CLK	6.3		5.5		ns



over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Load Circuit and **Voltage Waveforms)**

				C to 5°C	−40°C to	UNIT	
			MIN	MAX	MIN	MAX	
	Setup time	Data	4.9		4.3		ns
^L su	Setup time	PRE or CLR inactive					ns
t _h	Hold time	Data after CLK↑	0		0		ns
t _{rec}	Recovery time, before CLK↑	CLR↑ or PRE↑	4.7		4.1		ns

4.8 Timing Requirements, $V_{CC} = 5 V \pm 0.5 V$

over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

			−55°C to 125°C		-40°C to	UNIT	
			MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency			110		125	MHz
	Pulse duration	PRE or CLR low	4		3.5		20
t _w	Pulse duration	CLK	4.5		3.9		ns
	Catura time	Data	3.5		3.1		ns
t _{su}	Setup time	PRE or CLR inactive					ns
t _h	Hold time	Data after CLK↑	0		0		ns
t _{rec}	Recovery time, before CLK↑	CLR↑ or PRE↑	2.7		2.4		ns

4.9 Switching Characteristics, V_{CC} = 1.5 V

over recommended operating free-air temperature range, V_{CC} = 1.5 V, C_L = 50 pF (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TO (OUTPUT)		−55°C to 125°C		-40°C to 85°C	
					MAX	MIN	MAX	
f _{max}				9		10		MHz
t _{PLH}	CLK	O or O	Q or Q		125		114	no
t _{PHL}	CLK	QuiQ			125		114	ns
t _{PLH}	PRE or CLR	0.05 0	0		132		120	
t _{PHL}	PRE UI CLK	Q of Q	Q or Q		144		131	ns

4.10 Switching Characteristics, V_{CC} = 3.3 V ± 0.3 V

over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	to C	-40°C to 85°C		UNIT	
PARAMETER	PROW (INPOT)	10 (001701)	MIN	MAX	MIN	MA X	ONT
f _{max}			79		90		MHz
t _{PLH}	CLK	${\sf Q}$ or $\overline{\sf Q}$	3.5	14	3.6	12.7	ns
t _{PHL}	GER	QuiQ	3.5	14	3.6	12.7	113
t _{PLH}	PRE or CLR	Q or $\overline{\mathbb{Q}}$	3.7	14.7	3.8	13.4	ne
t _{PHL}	FILE OF CER	Q 01 Q	4	16.1	4.1	14.6	ns

Product Folder Links: CD54AC74 CD74AC74

4.11 Switching Characteristics, $V_{CC} = 5 V \pm 0.5 V$

over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	−55°C 125°		−40°C to	85°C	UNIT
	TROM (INFOT)	10 (0011-01)	MIN	MAX	MIN	MA X	
f _{max}			110		125		MHz
t _{PLH}	CLK	Q or Q	2.5	10	2.6	9.1	ns
t _{PHL}	GER	Q OI Q	2.5	10	2.6	9.1	115
t _{PLH}	PRE or CLR	Q or Q	2.6	10.5	2.7	9.5	20
t _{PHL}	PRE OF CER	Q 01 Q	2.9	11.5	3	10.4	ns

4.12 Operating Characteristics

 $T_A = 25^{\circ}C$

	PARAMETER	TYP	UNIT
C _{pd}	Power dissipation capacitance	55	pF



5 Parameter Measurement Information

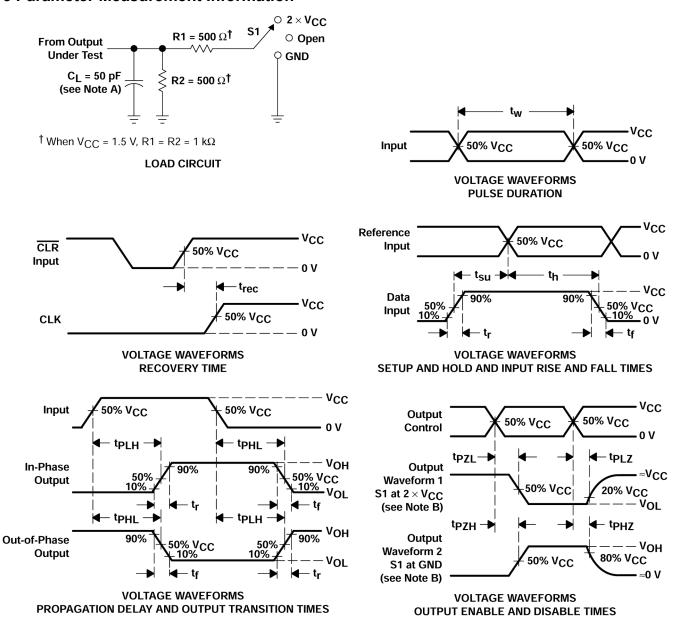


Figure 5-1. Load Circuit and Voltage Waveforms

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- A. C_L includes probe and test-fixture capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_r = 3 ns, t_f = 3 ns. Phase relationships between waveforms are arbitrary.
- D. For clock inputs, f_{max} is measured with the input duty cycle at 50%.
- E. The outputs are measured one at a time with one input transition per measurement.
- F. t_{PLH} and t_{PHL} are the same as t_{pd} .
- G. t_{PZL} and t_{PZH} are the same as t_{en}.
- H. t_{PLZ} and t_{PHZ} are the same as t_{dis} .

TEST	S1
t _{PLH} /t _{PHL}	Open
t _{PLZ} /t _{PZL}	2 × V _{CC}
t _{PHZ} /t _{PZH}	GND

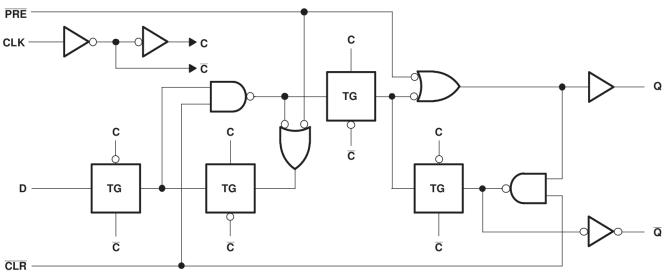
6 Detailed Description

6.1 Overview

The 'AC74 dual positive-edge-triggered devices are D-type flip-flops.

A low level at the preset (PRE) or clear (CLR) inputs sets or resets the outputs, regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the data (D) input meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not related directly to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

6.2 Functional Block Diagram



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Figure 6-1.

6.3 Device Functional Modes

Table 6-1. Function Table (Each Flip-flop)

		OUTPL	ITS		
PRE	CLR	CLK D		Q	Q
L	Н	Х	Х	Н	L
Н	L	Х	Х	L	Н
L	L	Х	Х	H ⁽¹⁾	H ⁽¹⁾
Н	Н	↑	Н	Н	L
Н	Н	1	L	L	Н
Н	Н	L	Х	Q_0	\overline{Q}_0

(1) This configuration is nonstable; that is, it does not persist when PRE or CLR returns to its inactive (high) level.

7 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

Power Supply Recommendations

The power supply may be any voltage between the minimum and maximum supply voltage rating located in *Section 4.3*.

Each V_{CC} terminal must have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for devices with a single supply. If there are multiple V_{CC} terminals, then 0.01- μ F or 0.022- μ F capacitors are recommended for each power terminal. It is permissible to parallel multiple bypass capacitors to reject different frequencies of noise. Multiple bypass capacitors may be paralleled to reject different frequencies of noise. The bypass capacitor must be installed as close to the power terminal as possible for the best results.

7.1 Layout

7.1.1 Layout Guidelines

Inputs must not float when using multiple bit logic devices. In many cases, functions or parts of functions of digital logic devices are unused. Some examples include situations when only two inputs of a triple-input AND gate are used, or when only 3 of the 4-buffer gates are used. Such input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states.

Specified in Layout Example for the CD74AC74 are rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, they are tied to GND or V_{CC} , whichever makes more sense or is more convenient.

7.1.2 Layout Example

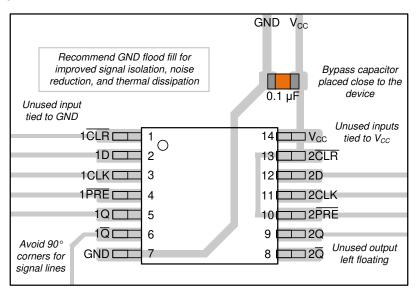


Figure 7-1. Example layout for the CD74AC74

8 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

8.1 Documentation Support (Analog)

8.1.1 Related Documentation

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 8-1. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
CD54AC74	Click here	Click here	Click here	Click here	Click here
CD74AC74	Click here	Click here	Click here	Click here	Click here

8.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

8.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

8.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

8.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

8.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

9 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision D (December 2002) to Revision E (August 2024)

Page

- Added Device Information table, Pin Functions table, ESD Ratings table, Thermal Information table, Device Functional Modes, Application and Implementation section, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section



10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
CD54AC74F3A	Active	Production	CDIP (J) 14	25 TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	CD54AC74F3A
CD54AC74F3A.A	Active	Production	CDIP (J) 14	25 TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	CD54AC74F3A
CD74AC74E	Active	Production	PDIP (N) 14	25 TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74AC74E
CD74AC74E.A	Active	Production	PDIP (N) 14	25 TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74AC74E
CD74AC74M	Obsolete	Production	SOIC (D) 14	-	-	Call TI	Call TI	-55 to 125	AC74M
CD74AC74M96	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC74M
CD74AC74M96.A	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC74M
CD74AC74M961G4	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC74M
CD74AC74M961G4.A	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC74M

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No. RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

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and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF CD54AC74, CD74AC74:

Catalog : CD74AC74

Military: CD54AC74

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CD74AC74E	N	PDIP	14	25	506	13.97	11230	4.32
CD74AC74E	N	PDIP	14	25	506	13.97	11230	4.32
CD74AC74E.A	N	PDIP	14	25	506	13.97	11230	4.32
CD74AC74E.A	N	PDIP	14	25	506	13.97	11230	4.32



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



CERAMIC DUAL IN LINE PACKAGE



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4040083-5/G





CERAMIC DUAL IN LINE PACKAGE



NOTES:

- 1. All controlling linear dimensions are in inches. Dimensions in brackets are in millimeters. Any dimension in brackets or parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This package is hermitically sealed with a ceramic lid using glass frit.
- His package is remitted by sealed with a ceramic its using glass mit.
 Index point is provided on cap for terminal identification only and on press ceramic glass frit seal only.
 Falls within MIL-STD-1835 and GDIP1-T14.



CERAMIC DUAL IN LINE PACKAGE



N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



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Last updated 10/2025